

# Performance report for SiT9386 - 74.25 MHz, LVDS

### **Conditions:**

- Frequency 74.25 MHz

- VDD: 2.5 V, 3.3 V

Room temperature

- Termination:

 $\circ$  100  $\Omega$  between both outputs.

# **Equipment:**

| Model                        | Measurement / Purpose                                |
|------------------------------|--|
| Keysight DSA90604A (6 GHz,   | Period jitter, differential voltage swing, rise/fall |
| 20 Gsps)                     | time, duty cycle                                     |
| Keysight 5052B Signal Source | Phase noise, integrated phase jitter                 |
| Analyzer                     |  |
| Keysight 34980A              | Power supply current                                 |
| Keysight E3631A              | Power supply   |
| Keysight 53230A              | Frequency  |

# Test setup:

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 100  $\Omega$  differential. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 1 shows test setup diagram for waveform parameters measurement.

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|----------------|-------|---|-------|----------------|--|
|                | Type: | Performance report                              | Rev:  | 1.0            |  |
|                | Orig: |   | Date: | April 16, 2018 |  |

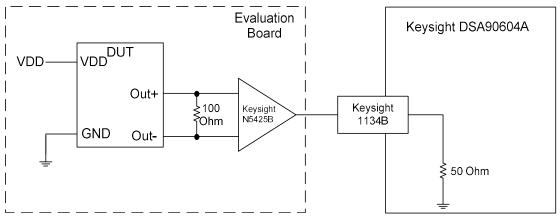


Figure 1: Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

For period jitter measurement outputs are connected through AC-coupling capacitors to the oscilloscope channels. Signals are subtracted inside the oscilloscope. All measurements applied to differential waveform. Figure 2 shows test setup diagram for period jitter measurement.

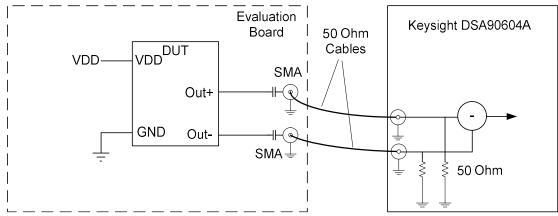
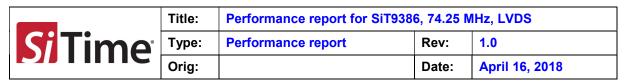


Figure 2: Test setup for measuring period jitter

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Figure 3 shows test setup diagram for phase noise measurement.



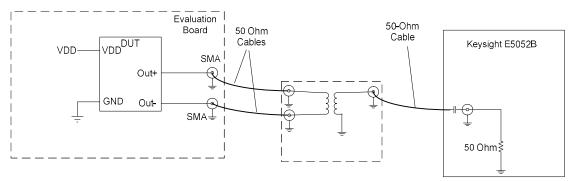


Figure 3: Test setup for measuring phase noise.

For IDD measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.

#### Data:

- Phase noise
- Integrated phase jitter
- RMS period jitter
- Peak-to-peak period jitter
- Rise/fall time
- Duty cycle
- Differential output swing
- IDE
- Frequency stability over temperature

Table 1: Summary performance data

| Parameter                                      |           | Voltage |       |
|--|-----------|---------|-------|
| Falametel                                      | Units     | 2.5 V   | 3.3 V |
| Integrated Phase jitter (1.875 MHz - 20 MHz)   | fs, rms   | 207     | 210   |
| Integrated Phase jitter (12 kHz - 20 MHz)      | fs, rms   | 283     | 285   |
| Period jitter                                  | ps, rms   | 0.85    | 0.81  |
| Period jitter (10,000 cycles)                  | ps, pk-pk | 6.44    | 6.34  |
| Duty cycle                                     | %         | 49.9    | 49.9  |
| Rise time (20% - 80%)                          | ps        | 331     | 328   |
| Fall time (80% - 20%)                          | ps        | 326     | 325   |
| Differential voltage swing                     | V         | 0.67    | 0.68  |
| Current consumption (no load, output enabled)  | mA        | 67.1    | 67.6  |
| Current consumption (no load, output disabled) | mA        | 51.3    | 51.8  |

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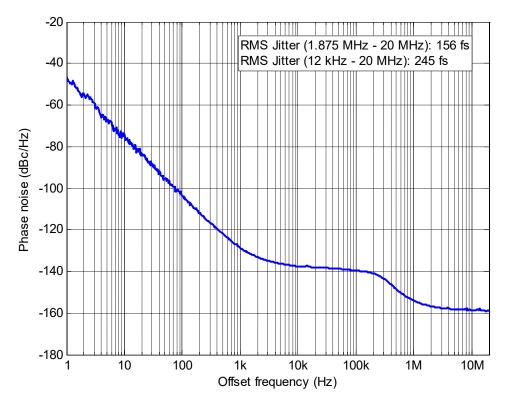


Figure 4: Phase noise, 2.5 V



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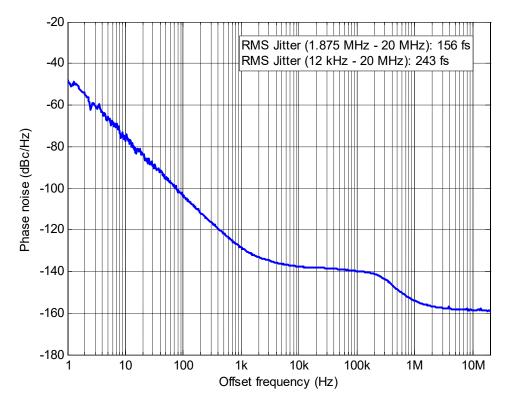


Figure 5: Phase noise, 3.3 V

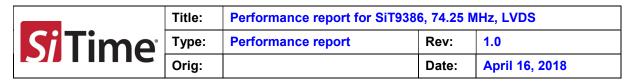




Figure 6: Output waveform, 2.5 V

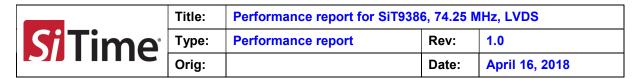




Figure 7: Output waveform, 3.3 V



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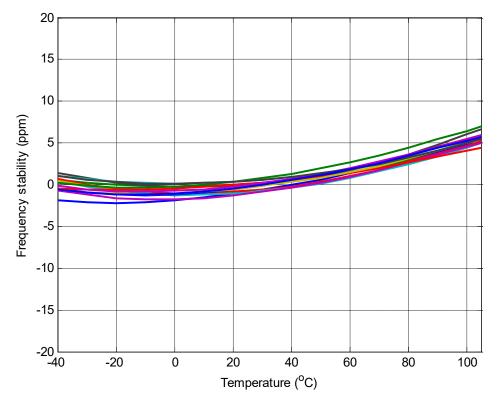


Figure 8: Frequency stability\* over temperature, 2.5 V

\*SiT9386 frequency stability is independent of output frequency.



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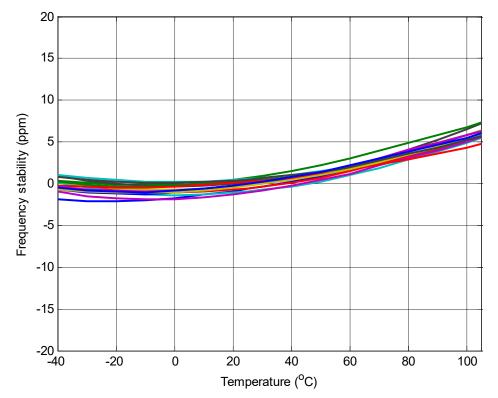


Figure 9: Frequency stability over temperature, 3.3 V